

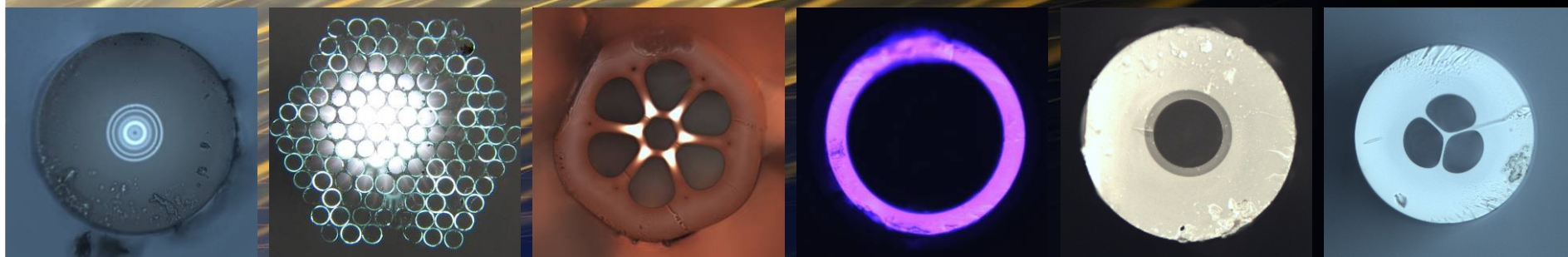


**Institute of Photonics and
Electronics v.v.i. (www.ufe.cz)**

Technology of Optical Fibers

FILANO team

www.ufe.cz/dpt240, www.ufe.cz/~kasik



Ústav fotoniky a elektroniky AV ČR, v.v.i.



*Prof. Jiří Homola
Česká hlava 2009*



ZÁKLADNÍ VÝZKUM:

fotonika

- vláknové lasery a zesilovače, **optická vlákna**
- optické biosenzory
- státní etalon času, detekce pole živých buněk

100 FTE

Outline

Intro

Optical fibers

Technologies

Preform preparation – MCVD & others
silica properties – MCVD vers. conventional
fiber drawing

Application

Telecommunications, fiber lasers,
amplifiers, sensors

Summary

LABO

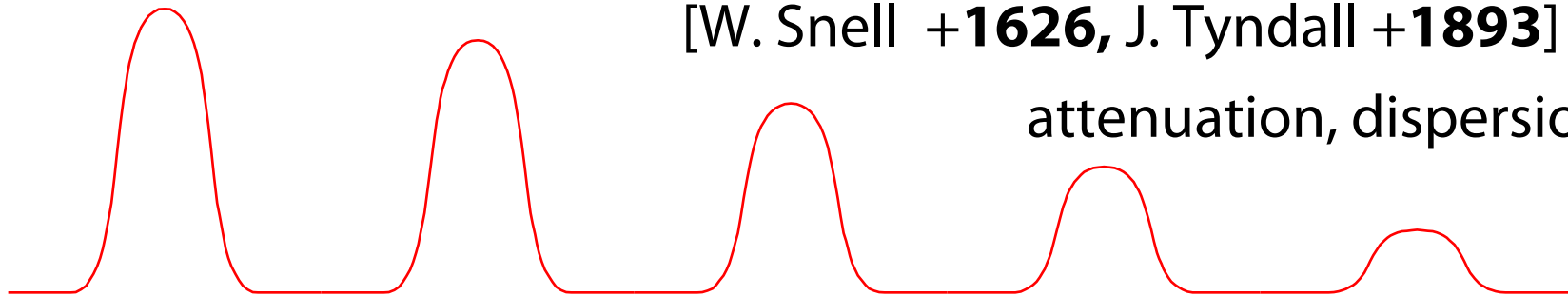
MCVD, fiber drawing, sol-gel,
magnetron sputtering

Optical fiber

Optical fiber : dielectric structure, $L \ll r, n_{\text{core}} > n_{\text{clad}}$

[W. Snell +1626, J. Tyndall +1893]

attenuation, dispersion



Optical losses in optical fibers

- transparency of 3 mm of window-glass \approx 2 km of optical fiber



[Ch.Kao, 1964]

Charles K. Kao

**Nobel prize
2009**



**high-purity materials
max impurities acceptable
in ppb (10^{-9})**



ULTRA-PURE TECHNOLOGIES

Purity of material



1. Per Analysis – PA (99 - 99,5 %)
2. Semiconductor – PP (99,9995 %)
3. **Ultra-pure - FO Optipur / for trace analysis [ppb]**

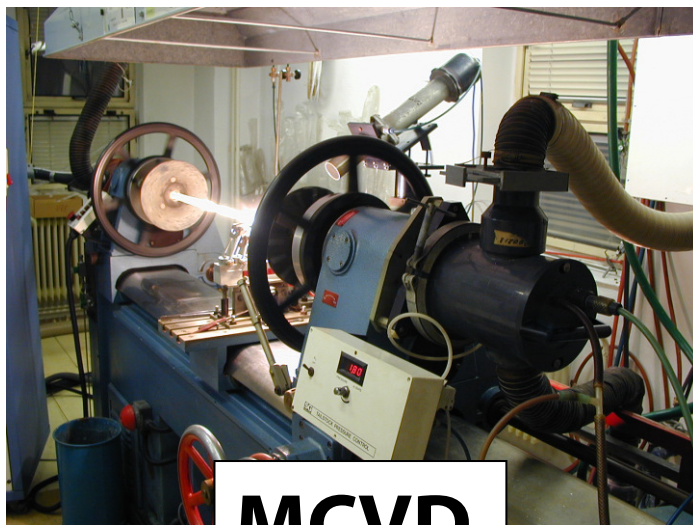
% – 10^{-2}

ppm – 10^{-6} (parts per million)

**ppb – 10^{-9} (parts per billion) : content of impurities
acceptable in FO Optipur materials**

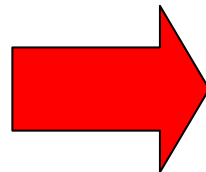
Ultra-pure technologies - CVD !

Optical fiber preparation

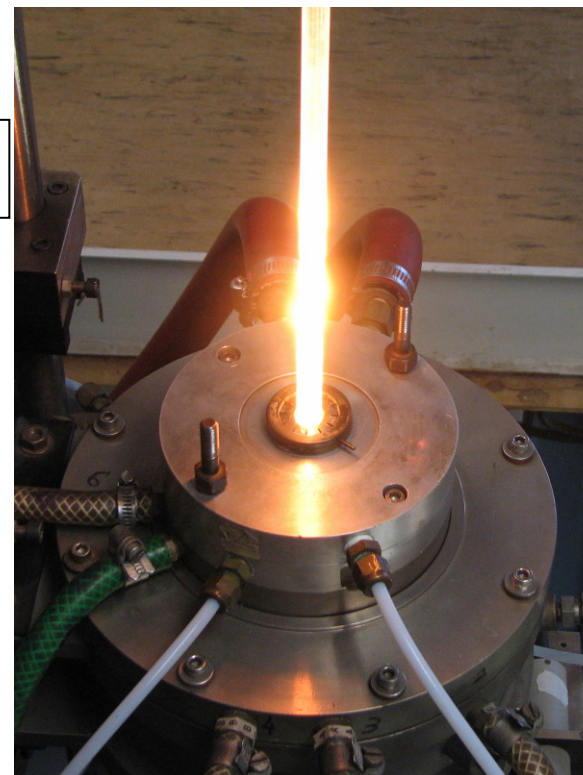


MCVD

1. Preform

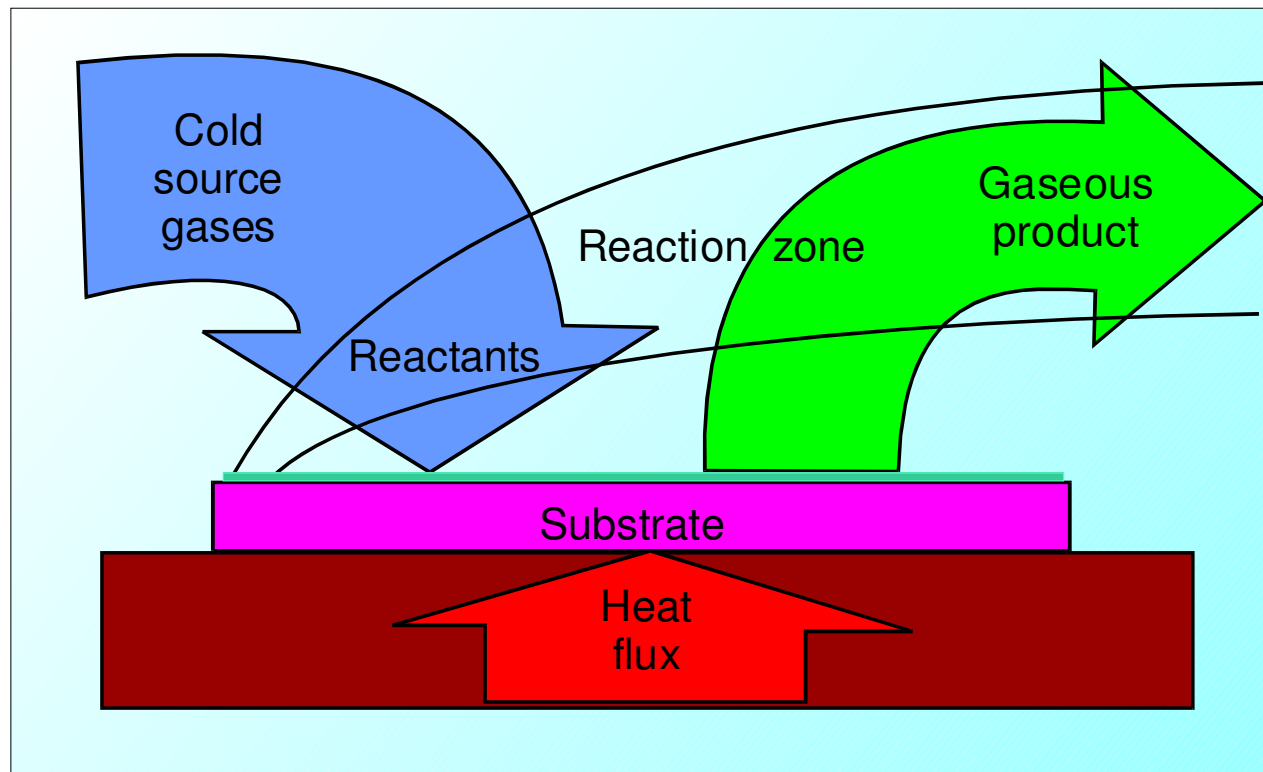


2. Fiber drawing



Ultra-pure technologies

CVD - Chemical Vapor Deposition



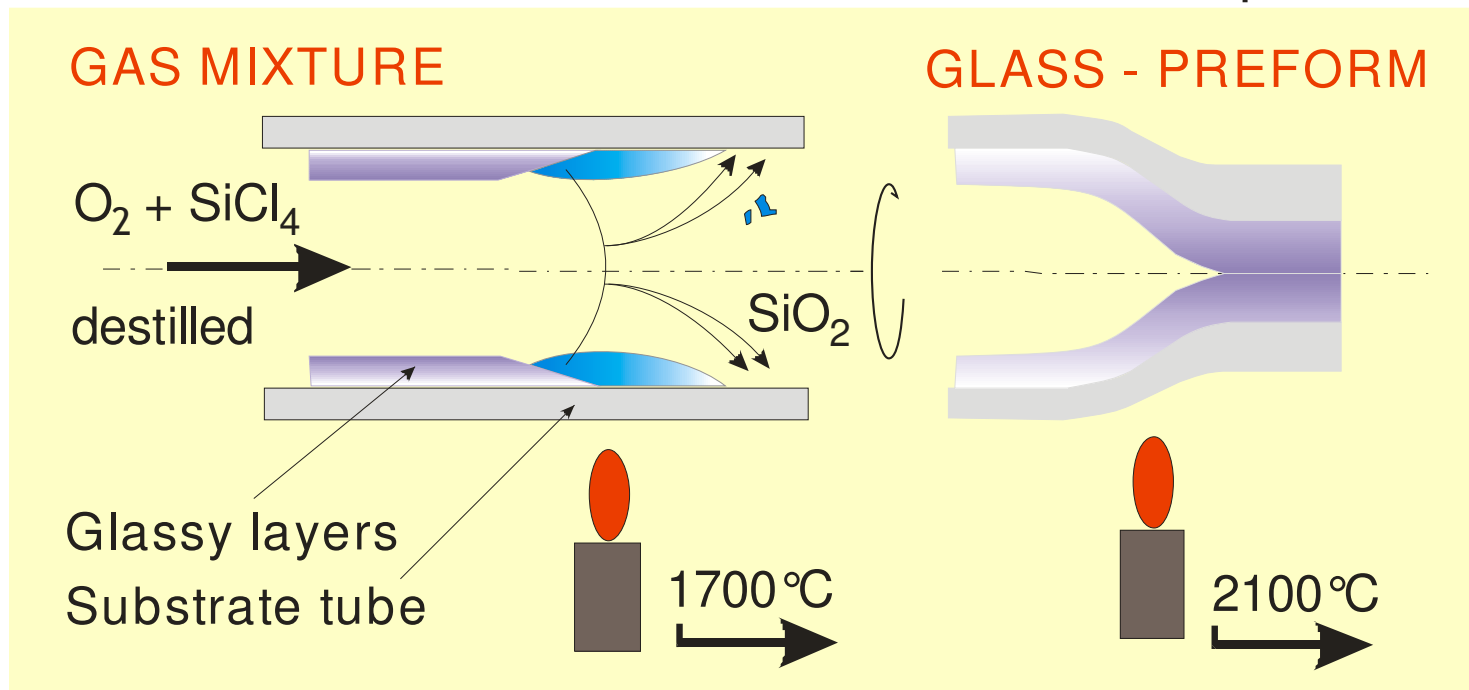
Goal : starting materials (g) or (l) can be purified (E.g. distilled)

Preform preparation

MCVD – (Modified) Chemical Vapor Deposition

1. Deposition of layers

2. Collapse



- Sequential sintering of **thin glassy layers** (of thickness 1-20 μm) onto inner wall of silica substrate **resulting in bulk material – preform** [S. R. Nagel, 1982]
- **high purity** ($\sim 10^1$ ppb) **high preciseness** (better than 1 %)

MCVD process model

1. Vaporization of starting materials

- $V_{\text{XCl}_4} = V_{\text{Ox}} \cdot P^{\circ}_{\text{XCl}_4} / (P - P^{\circ}_{\text{XCl}_4})$... boiling point $\text{SiCl}_4 = 56^{\circ}\text{C}$

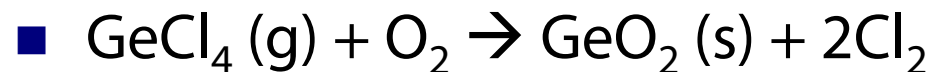
2. Oxidation

- 1st-order kinetics, $t = 0.02$ s

- Chemical equilibrium :



conversion $\sim 0.95 - 0.99$ (1500°C)



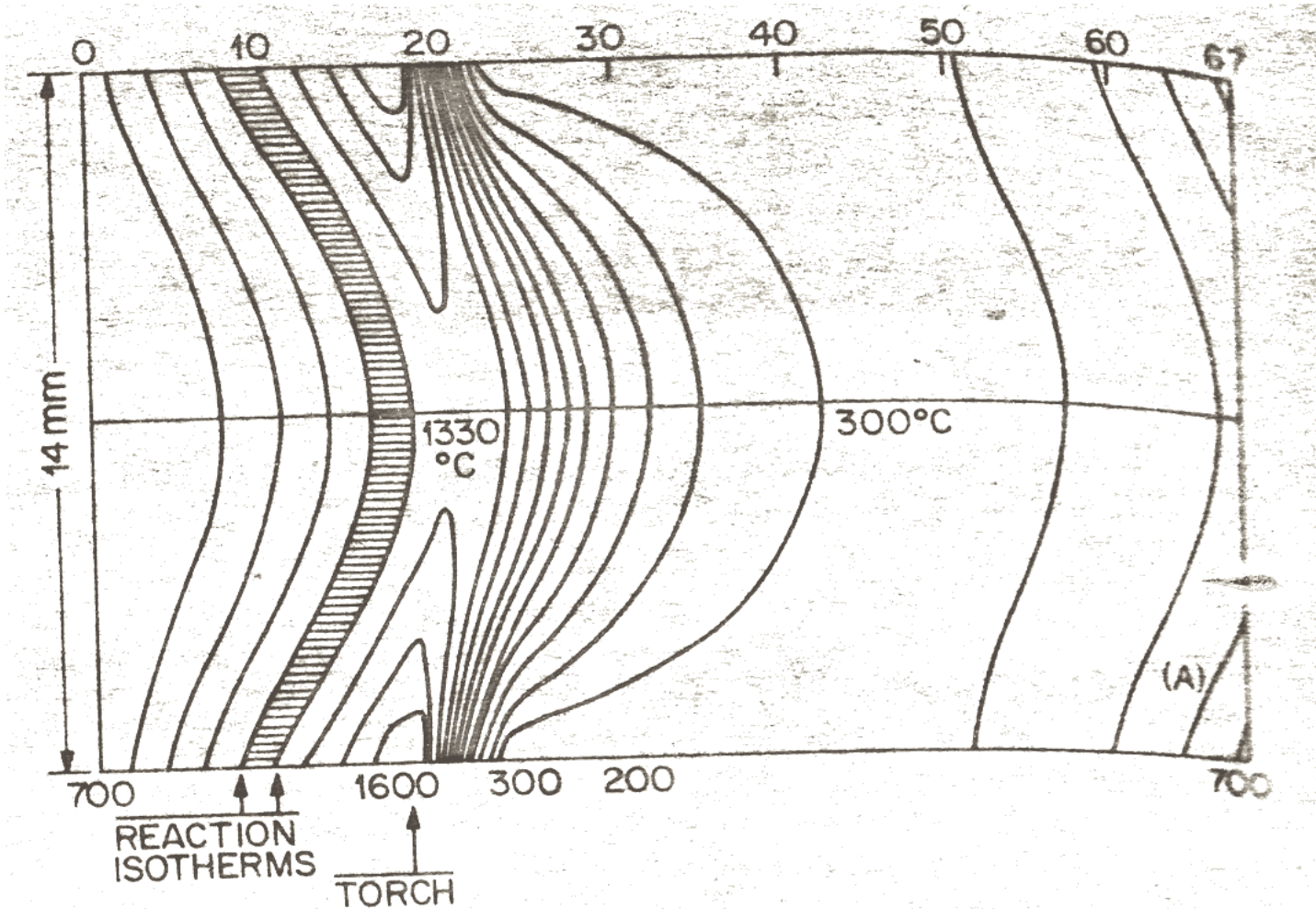
conversion $\sim 0.5 - 0.6$ (1600°C), $f(t, x_{\text{SiCl}_4}/x_{\text{GeCl}_4})$

3. Deposition

- Thermophoretic efficiency

$$E = K \cdot (1 - T_{\text{cool surface}} / T_{\text{reaction}}) \sim 0.6$$

MCVD process model



Temperature field during deposition

MCVD process model

Process parameters :

Variable :

- flow rates (Si, Ge, P, B, F, Ox ...)
- deposition temperature

Adjustable :

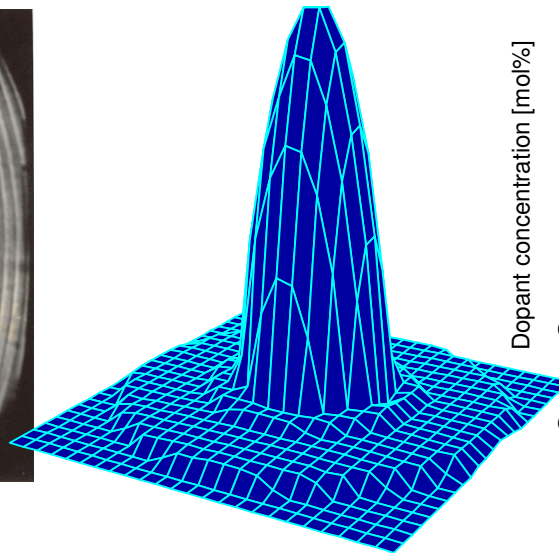
- temperature of starting materials (liquids)
- burner speed
- pressure
- rotation speed of the substrate tube
- substrate tube dimensions

[McChesney and Nagel, 1982, Wood, 1987, Kirchhof, 1986]

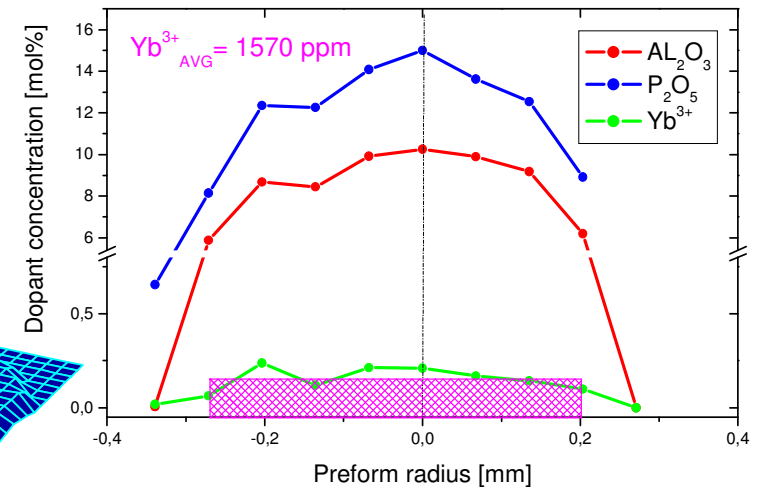
MCVD output parameters



Microphoto of cross section of preform



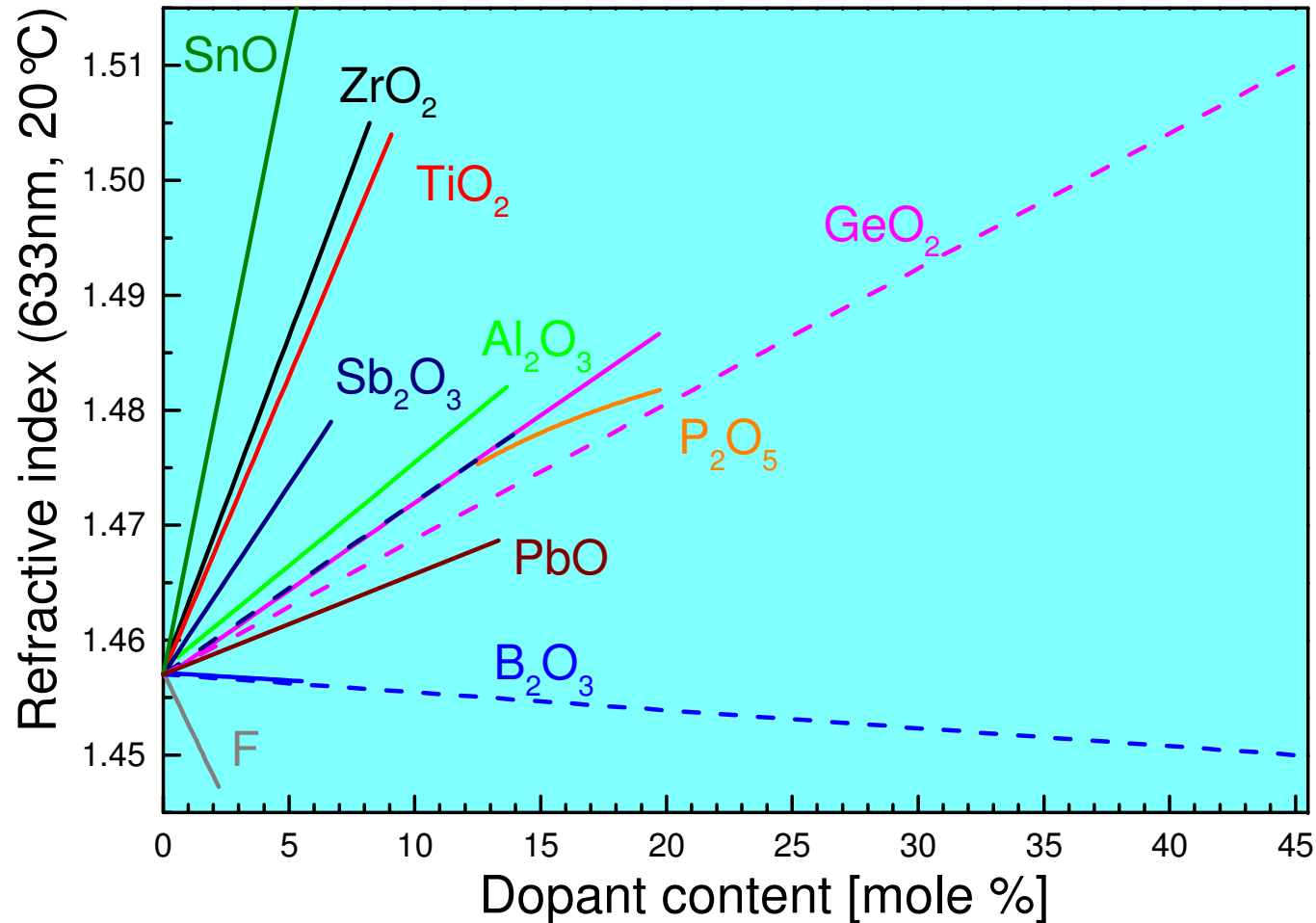
Tomography of the refractive-index profile of preform



Concentration profile

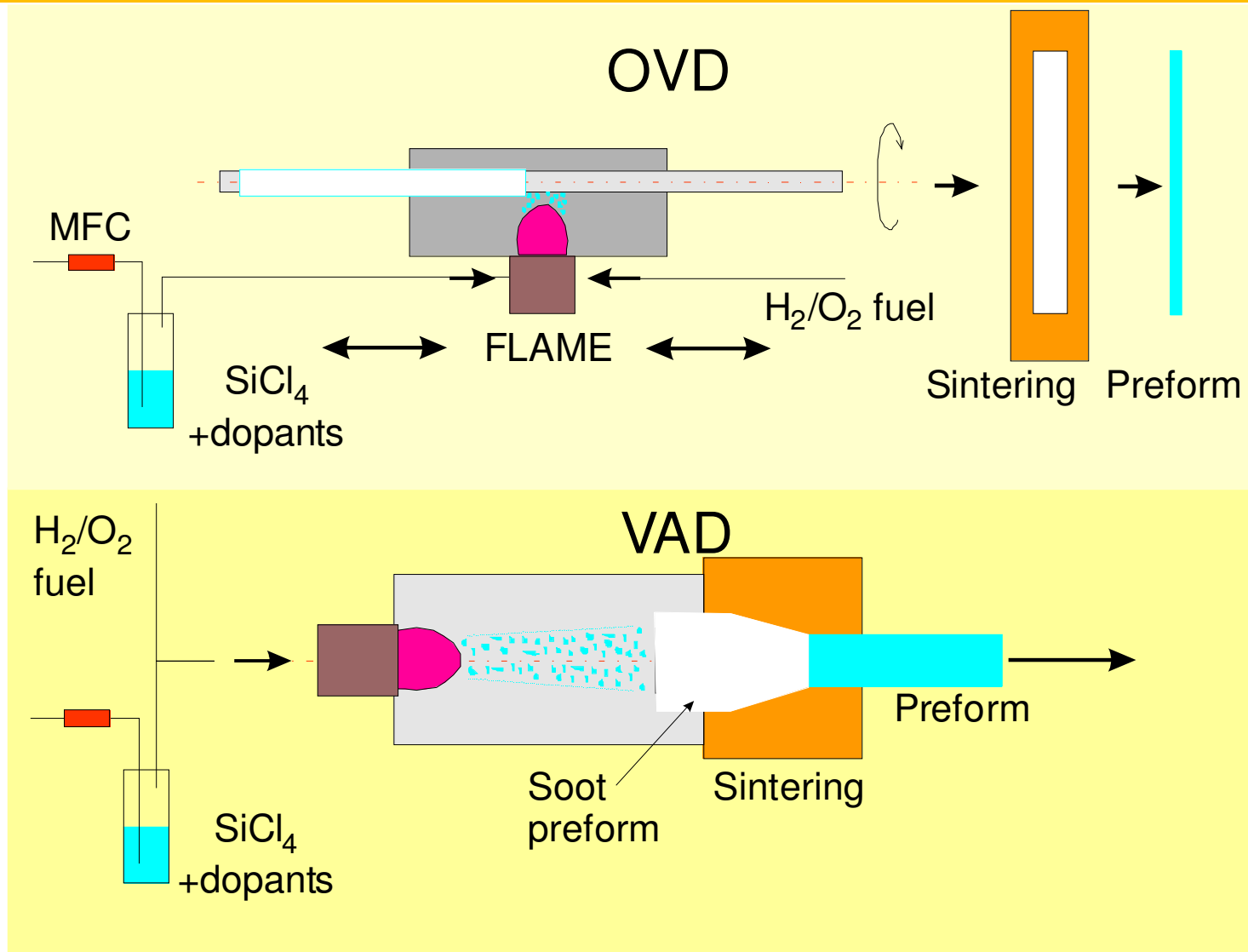
- High purity material due to FO-Optipur purity starting materials.
- High quenching rate ranging from 10^2 to 10^3 °C/s !

MCVD - doping of silica

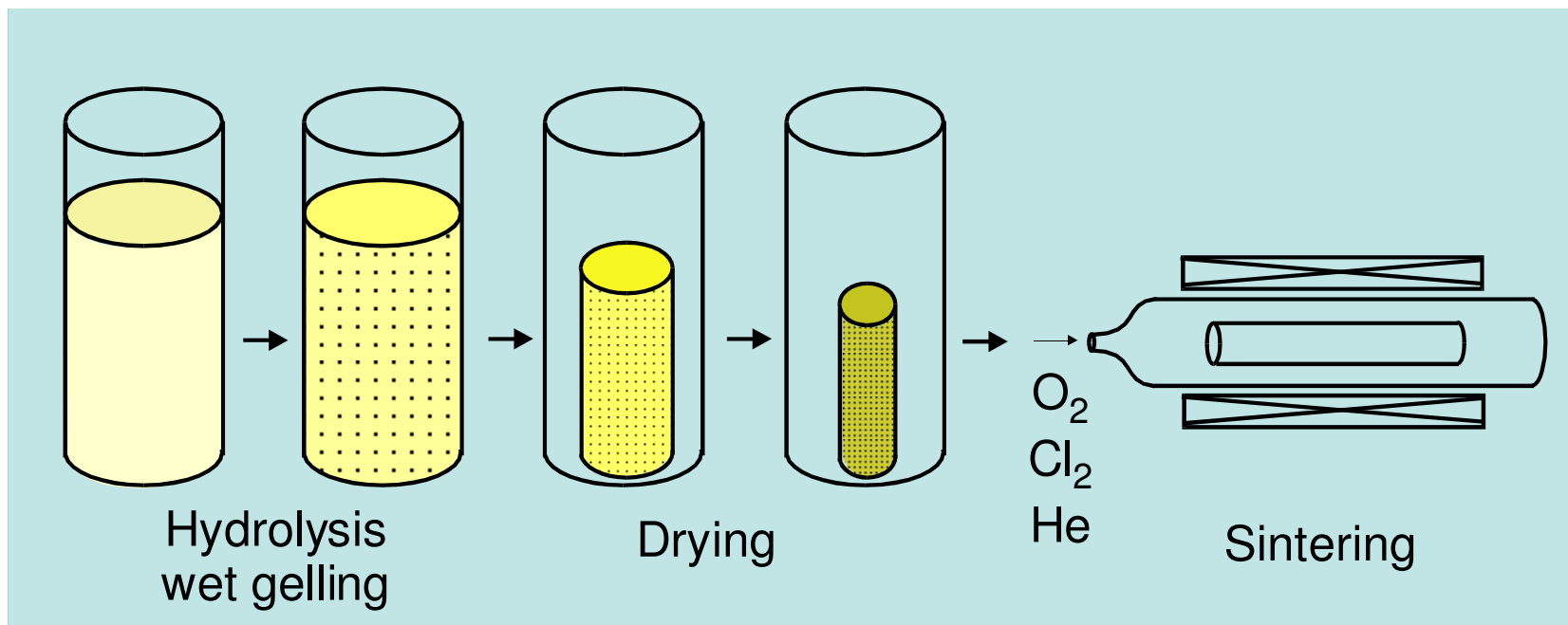


[A.B. Chynoweth, 1979, M. Shimizu, 1986, Y. Ohmori, 1983, S. H. Wemple, 1973, H. Wehr 1986, I. Kasik, 2005, K. Sanada, 1980, M. M. Karim 1994]

Other CVD technologies (ultra-pure)



Other technologies : sol-gel



No melting, disorder imprinted.

[J. McKenzie (US), J. B. McChesney, 1997, A. Pope (US), 1993, M. Guglielmi (It), J. Livage (F), R. Almeida (P), S. Ribeiro (Br), B. McCraith (Ir), J. Brinker (US), S. Sakka (J), V. Matejec & J. Mrazek (CZ)]

Comparison

CVD (Chemical)

x

PVD (Physical)

MCVD
OVD etc.

DC magnetron sputtering
vacuum evaporation etc.

Layer thickness

1 – 10¹ **μm**

1 - 10¹ **nm**

(however, both are reported as “thin layers”)

Deposition rate

HIGH

LOW

Products

Layers, bulks

Layers only

Comparison

(M)CVD

x

conventional

Starting materials

gaseous (g) or liquid (l)

melting point of oxides different

(s) solid state

melting point comparable

Purification methods

distillation

recrystallisation, remelting

Comparison

(M)CVD

x

conventional

Process

Deposition of layers

= oxidation+deposition+sintering

(NO MELTING)

Collapsing of preform (MELTING)

-

Melting

Forming

Annealing

Structure of products

Graded - profiles

Homogeneous

Material purity

ppb (10^{-9} , i.e. 10^{-7} mol%)

10^{-3} mol% (99,999%)

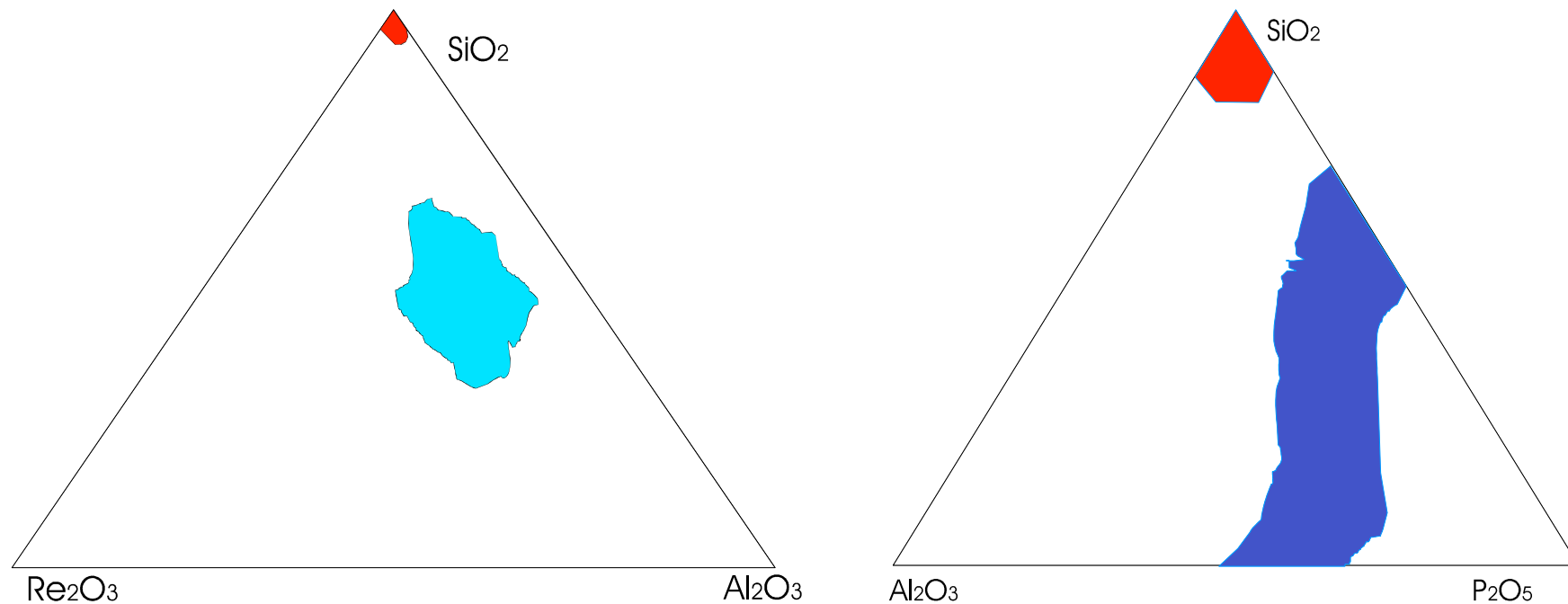
Properties

(M)CVD

x

conventional

Glassforming region



Quenching rate

$\sim 10^2 - 10^3 \text{ }^\circ\text{C/s}$

$\sim 10 \text{ }^\circ\text{C/min}$

[O. V. Mazurin, 1980, J. E. Shelby, 1992]

Properties

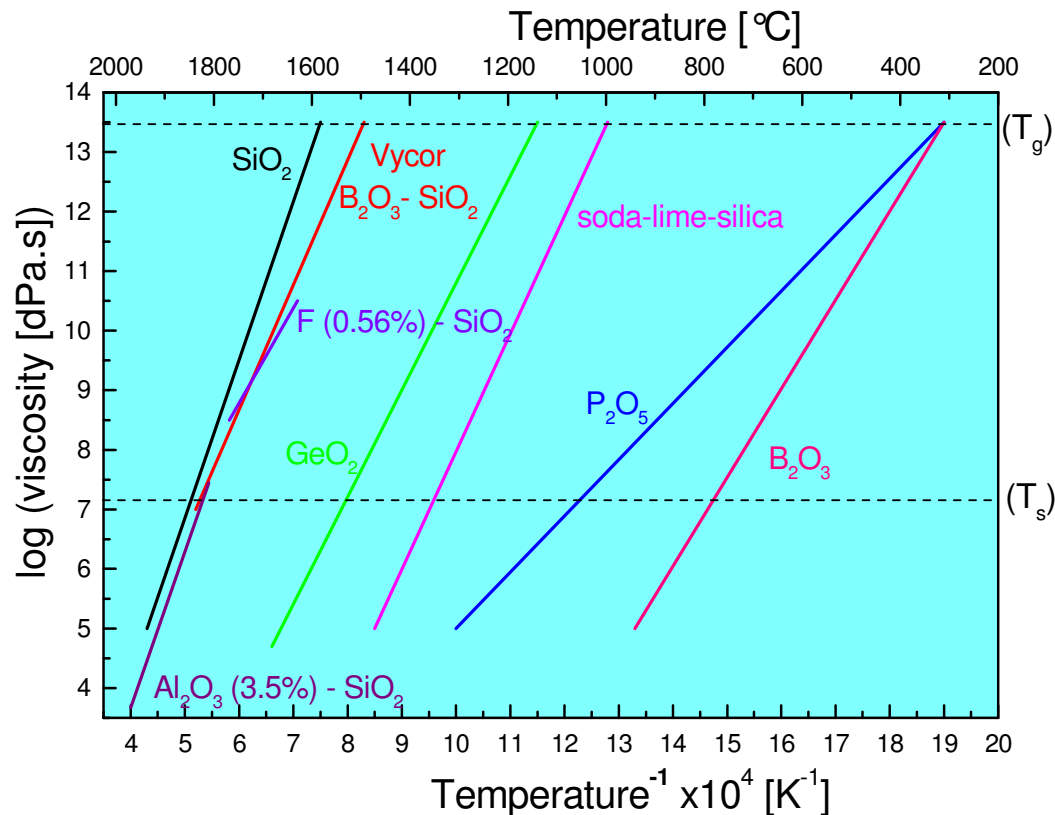
(M)CVD

x

conventional

Viscosity curves

Short



Long

Annealing ~ 1120-1180 °C [www.Heraeus, M. B. Volf, 1987, A. B. Chynoweth, 1979, M. Ohashi, 1992, O. V. Mazurin, 1980, K. Shiraki, 1993]

Properties

(M)CVD

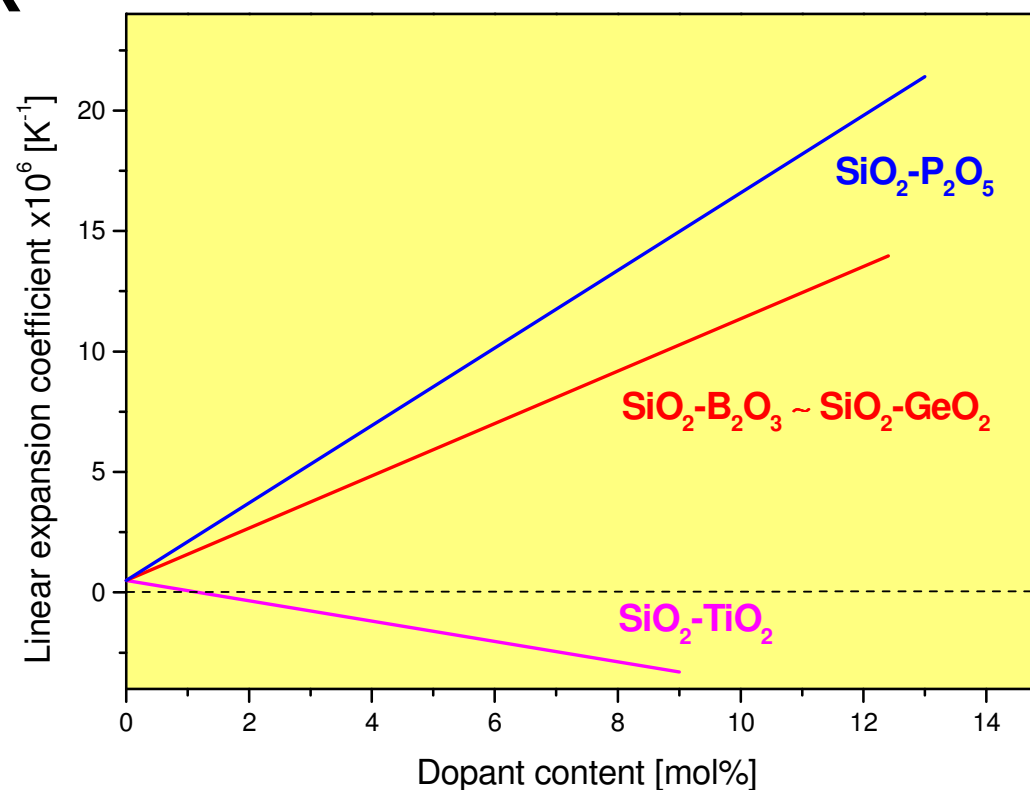
x

conventional

Expansion coefficient KLTR

$0.5 \cdot 10^{-6} \text{ K}^{-1}$

$< 3.3 \times 10^{-6} \text{ K}^{-1}$



[A. B. Chynoweth, 1979, O. V. Mazurin, 1980, S. H. Wemple, 1973]

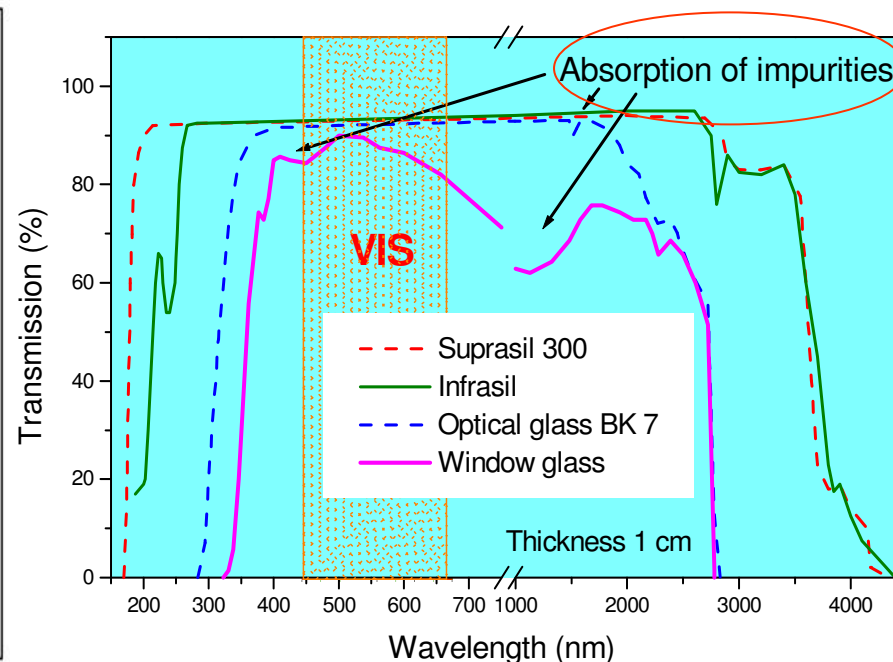
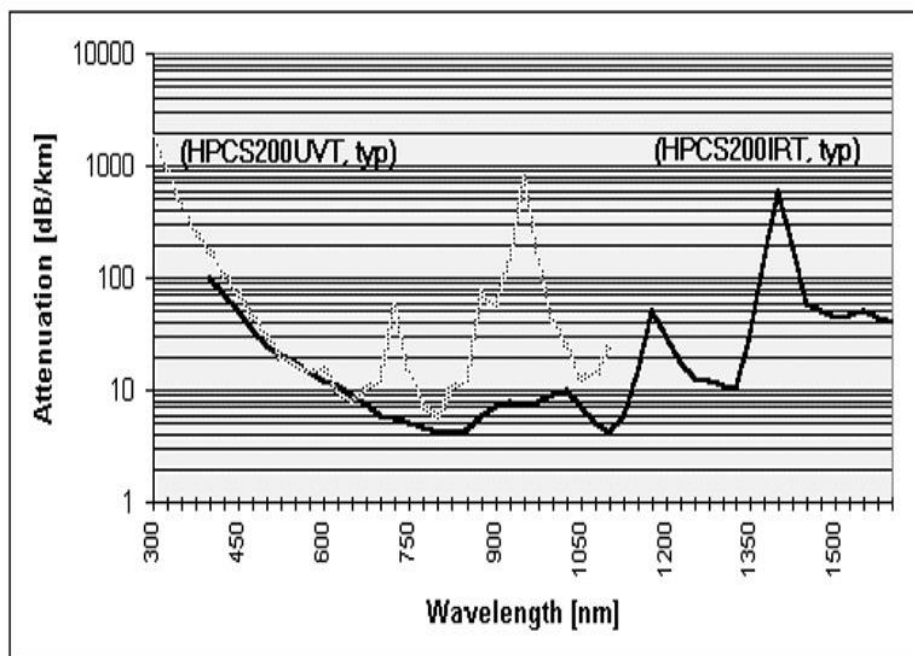
Properties

(M)CVD

x

conventional

Optical properties - transparency



Dependence of absorption at UV on technology of silica production

[Safibra, 2010 & M. B. Volf, 1987]

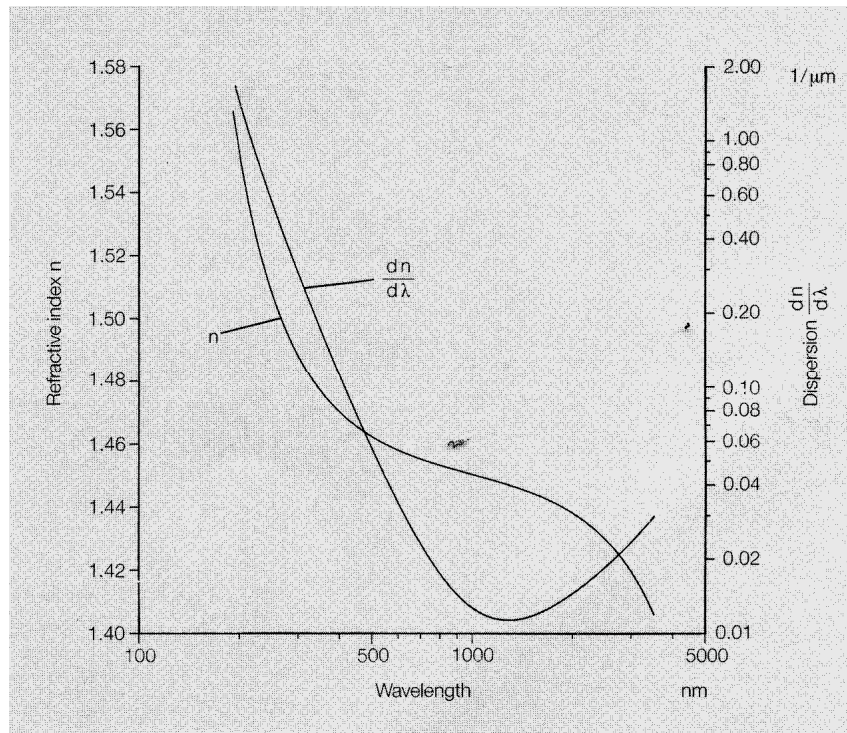
Properties

(M)CVD

x

conventional

Optical properties – refractive index



$$n_{633 \text{ nm}, 20^\circ\text{C}} = \mathbf{1.457}$$

$$n_{10.6 \mu\text{m}, 20^\circ\text{C}} < 1 \quad [\text{www.heraeus.de}]$$

$$1.48 < n < 1.95$$

$$[\text{www.schott.com}]$$

Comparison : GLASS

(M)CVD

x

conventional

GLASS : *solid state material, amorphous, usually produced by quenching of melt, in glassy state (stable below T_g) [Hlaváč, 1981]*

Structure

amorphous

amorphous

short-distance order (< 1 nm)

longer-distance disorder (>1 nm)

no X-ray crystallographic signal

nano-structure imprint feasible (glass/glassceramics)

Production - kinetics

sintering +

melting & quenching $\sim 10^2 - 10^3$ °C/s

melting +

quenching ~ 10 °C/min

[G. Tammann, 1933]

Comparison : GLASS

(M)CVD

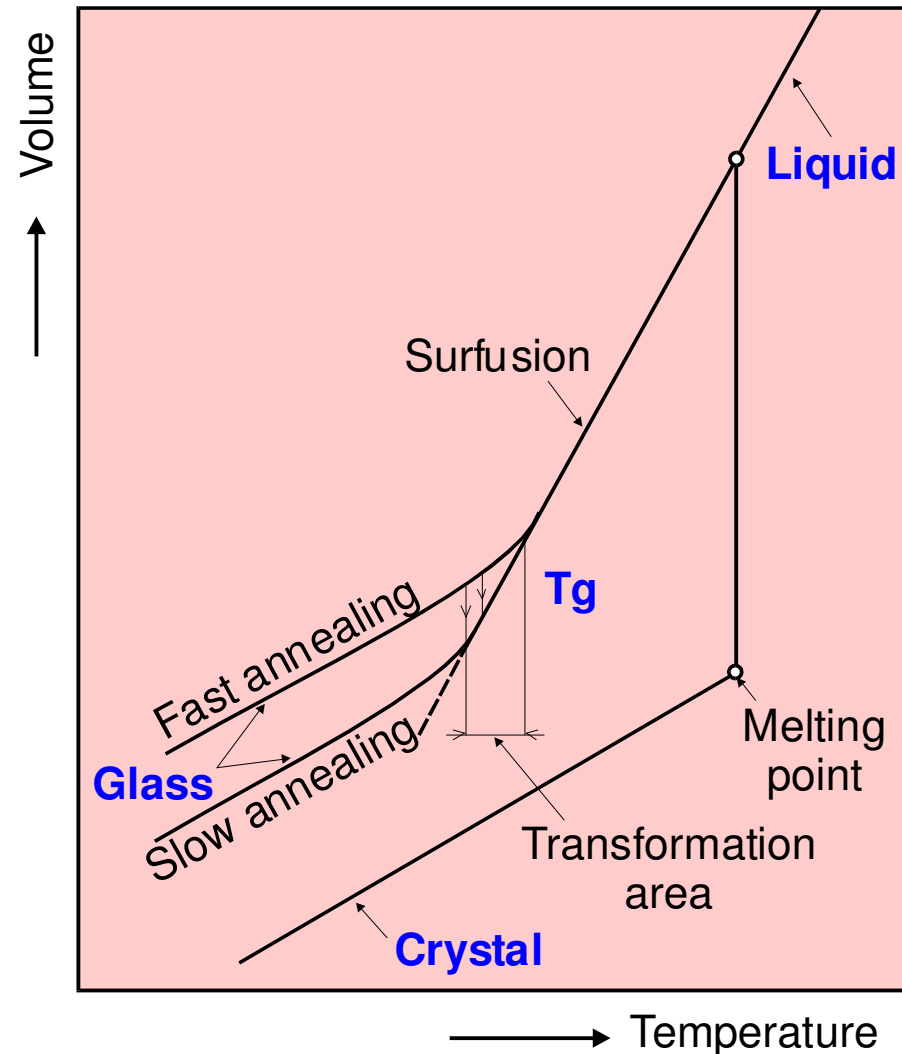
x

conventional

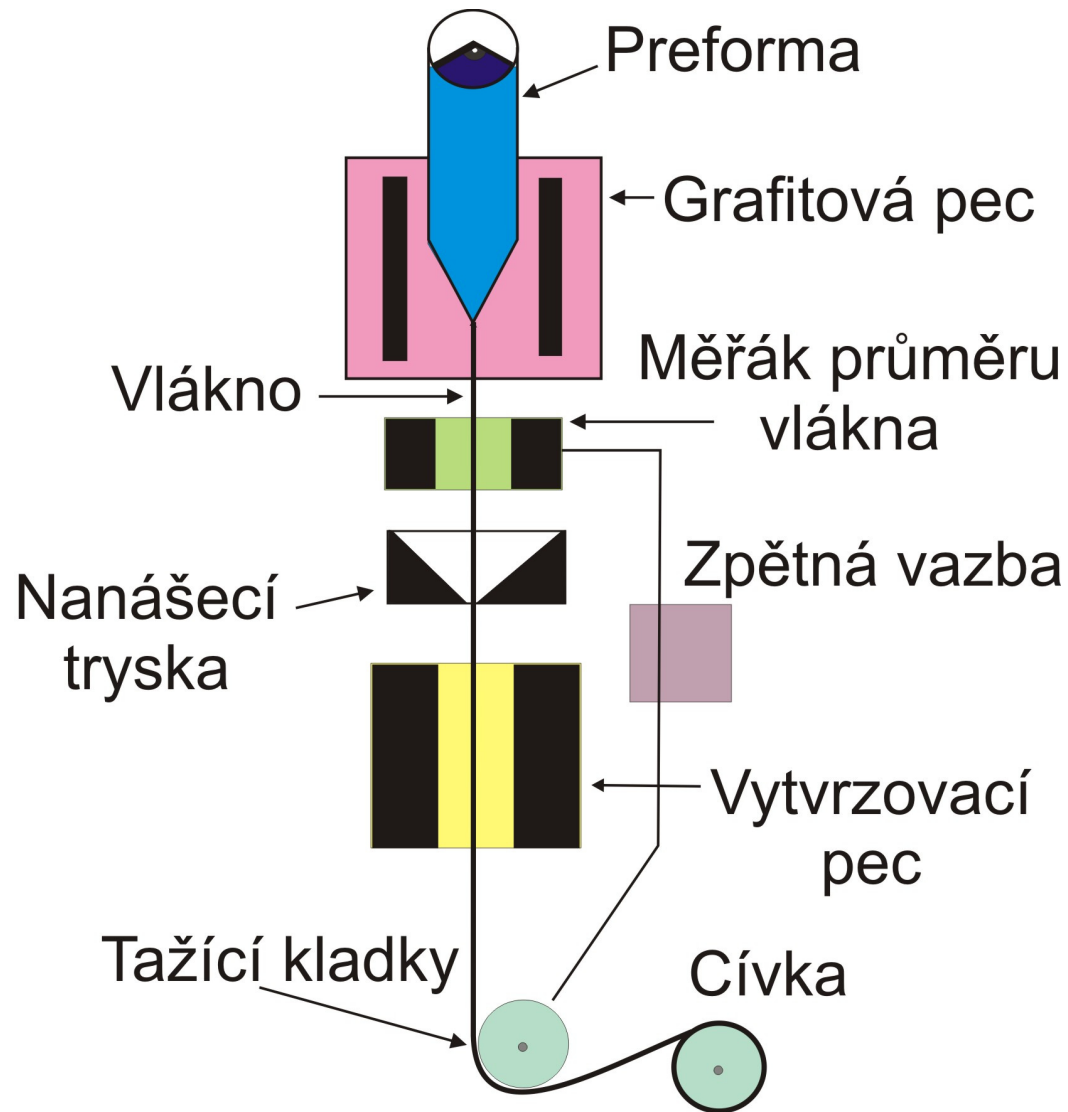
Thermodynamics

Glassy state : *stable bellow T_g*
(depending on quenching rate)

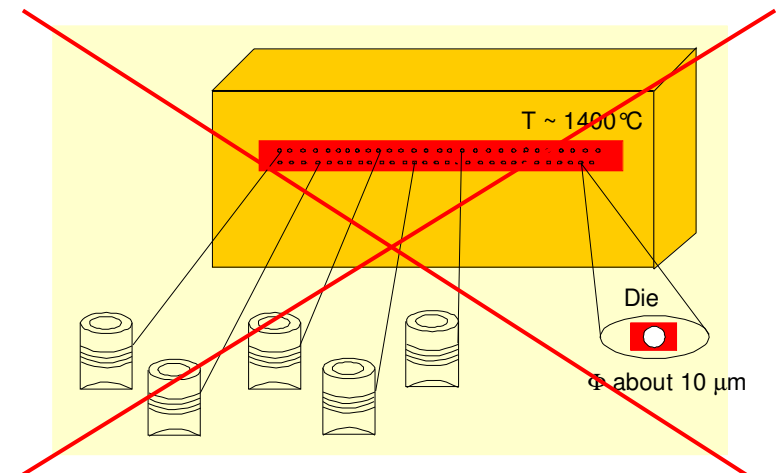
- extremely high quenching
- stable
- ? Reproducibility
- higher porosity
- lower density



Drawing of optical fibers



- diameter
80-1000 μm
- temperature 1800-2000 $^{\circ}\text{C}$
- No thermo-insulation
- No textile
- No nanofibers !



Comparison of fibers

optical

SILICA (doped with GeO_2 ,
 P_2O_5 , B_2O_3 ...)
High productivity (relative)

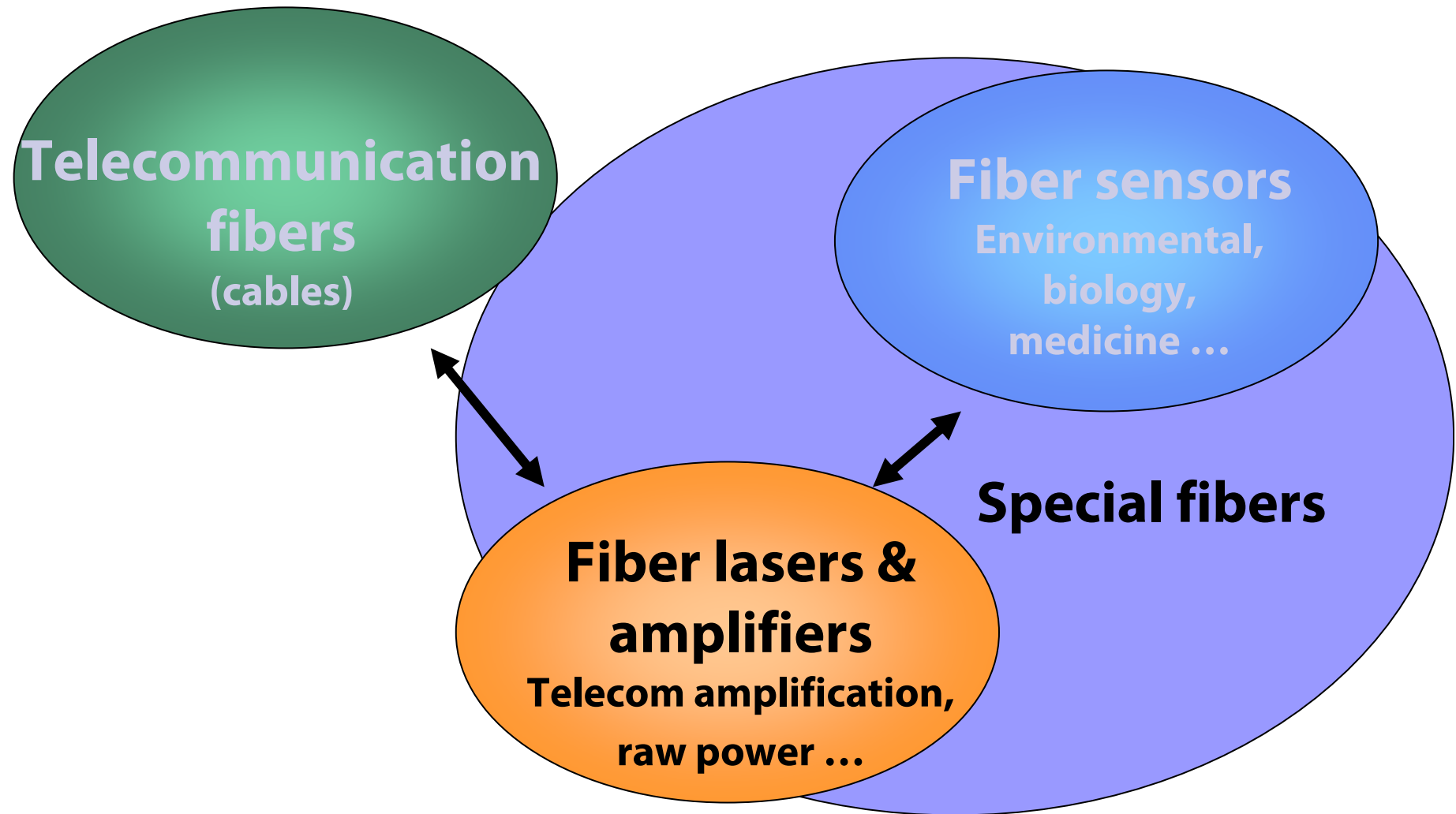
- Purity FO Optipur grade
- Chemical durability
- Precise geometry ($<0.5 \mu\text{m}$)
- Low optical loss $\sim 0.2 \text{ dB/km}$
- Strength $\sim 5 \text{ GPa}$ due to coating
- Use in **OPTICS**

x

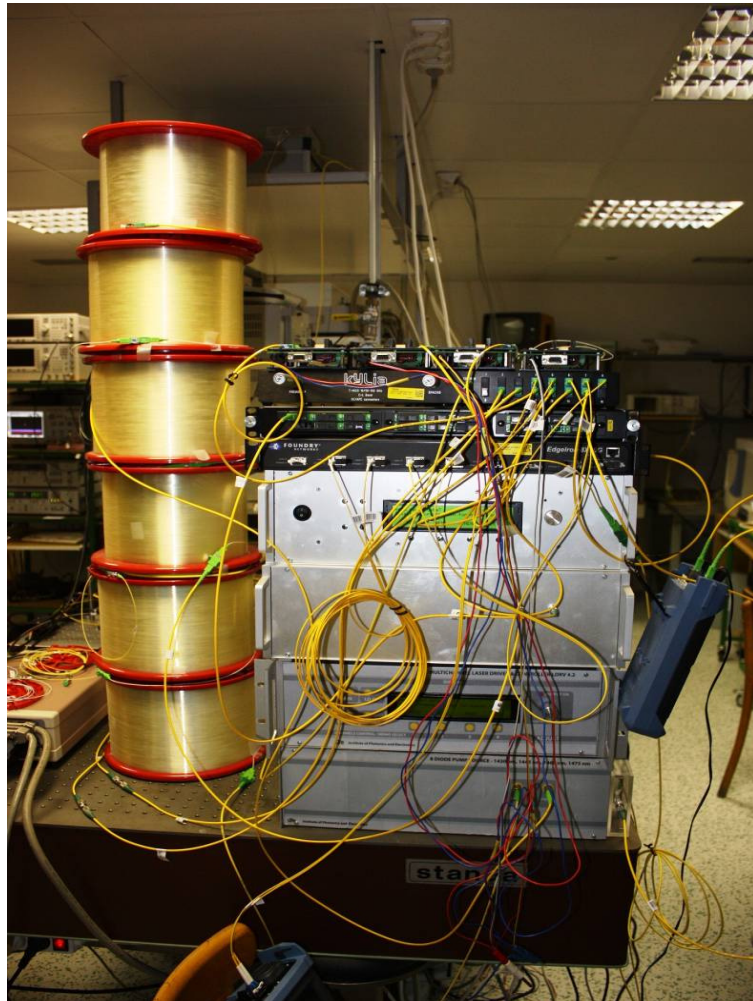
soft-glass

- $(\text{CaO}, \text{MgO})\text{-Al}_2\text{O}_3\text{-B}_2\text{O}_3\text{-SiO}_2$
- $\text{Na}_2\text{O} - \text{CaO} - (\text{Al}_2\text{O}_3) - \text{SiO}_2$
- High productivity – *low processing temperature, cheap starting materials*
- Thermo-insulating properties
- Chemical durability
- A geometry allowing weaving
- Strength $\sim 2.5 \text{ GPa}$ (without coating, temporary)
- Use as insulators and textiles

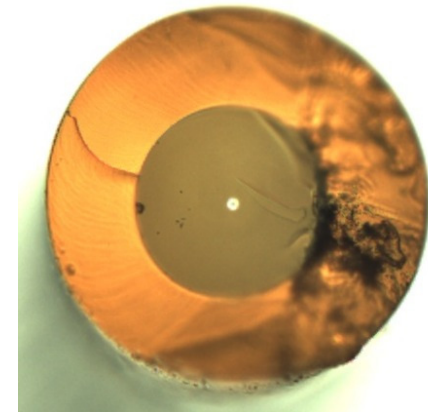
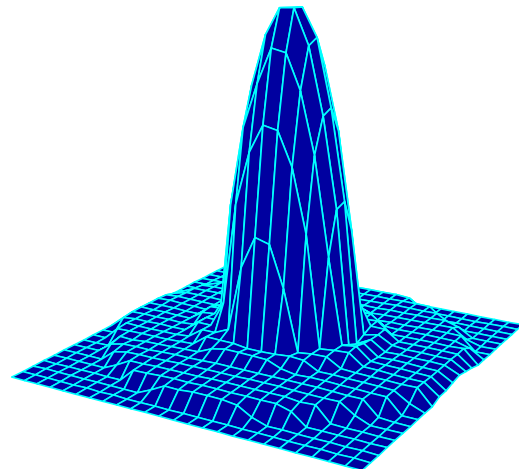
Application



Telecommunications



Testing of 200 km telecom line

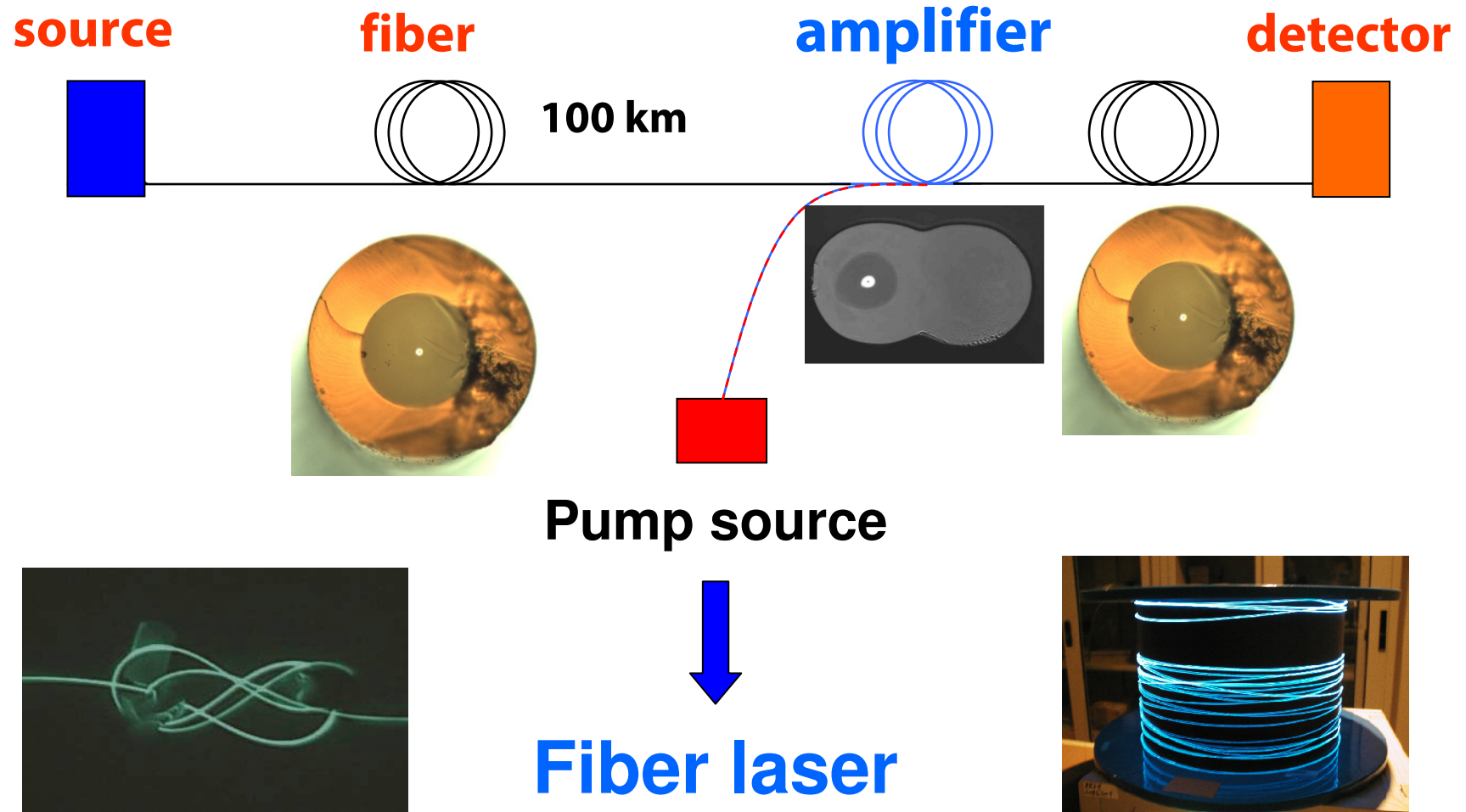


SM 1300, 1550 nm

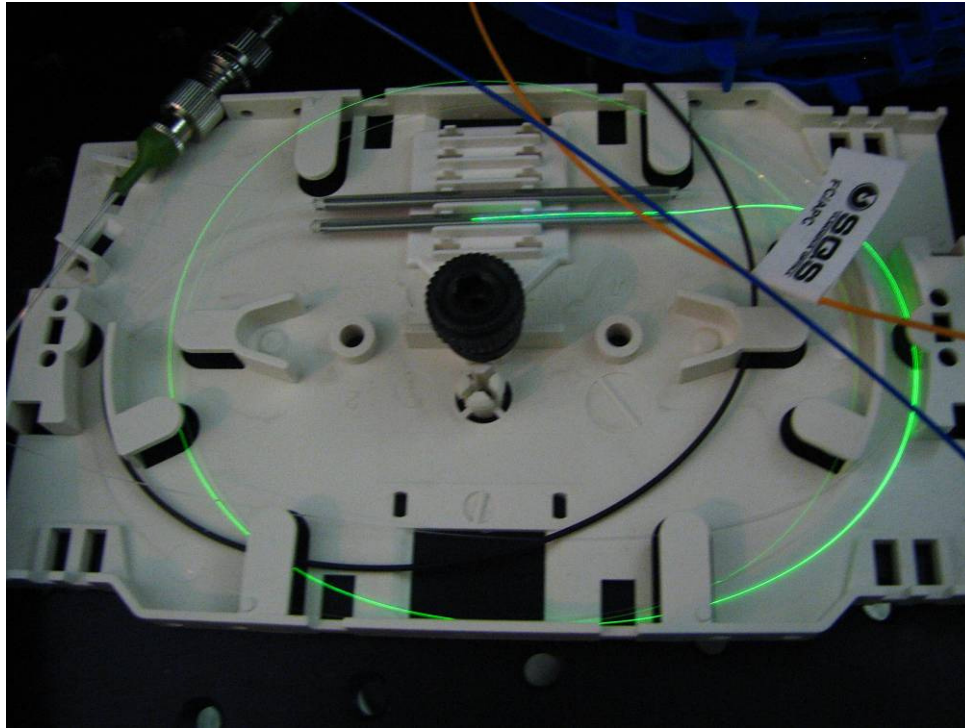
GI - technology transfer
VÚSU Teplice, Hesfibel TR

1981 – 1st demonstration of
CZ optical fiber – UFE/URE/JLS

Telecommunications : fiber lasers and amplifiers



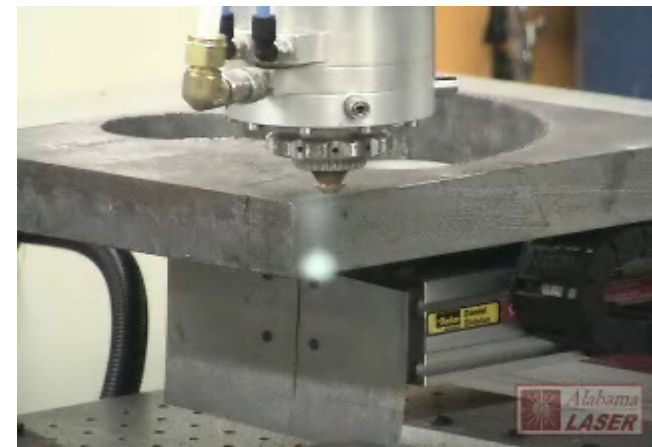
High power fiber lasers



	Intensity of light
Sun	63 MW/m ²
1W-fiber laser	12.7 GW/m ²

Er- fiber laser,
pulsed 197 fs,
5m resonator
Liekki

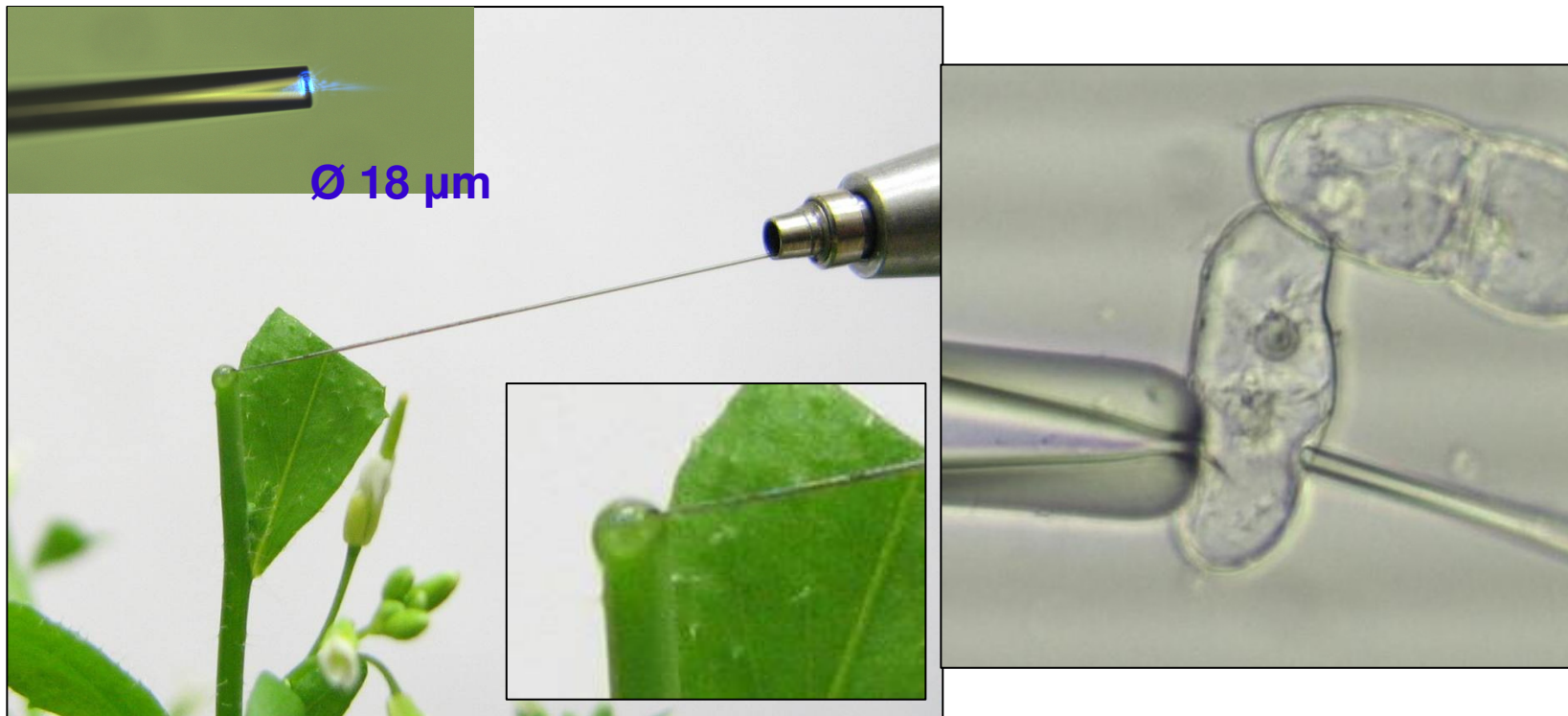
PALS



Welding, cutting < 2kW
savings, fast process

Fiber-optic sensors

Small devices capable of **continuous and reversible** monitoring of (bio)chemical species and their concentration



Principle : change of properties of the light due to chemical (physical) changes of medium.

SUMMARY

MCVD

Suitable for the preparation of :

- **silica-based** materials, **doped** (up to 50 mol%)
- **few-component** (up to ~ 6 components) materials
- materials for **photonics, optics**, optoelectronics
- materials of **high-level purity** (~ 10¹ ppb)
- products requiring high preciseness of geometry (better 1 %)

SUMMARY

1. **OF technology : preparation of structures of high preciseness from materials of ultra-high purity (impurities in ppbs only).**
2. **OF preparation in two steps : preform preparation and fiber drawing.**

(M)CVD technique (preform) makes possible to prepare multilayered tailored structures of suitable level of purity.

3. **Fibers conventional (passive) and specialty (active).**
4. **Research of optical fibers (CR) :**



References

- **J. M. Senior** : *Optical fiber communications - Principle and practise*, Pearson Education Limited, Harlow, England, 2009.
- **A. Mendez, F.T. Morse** : *Specialty optical fibers handbook*, Elsevier Science & Technol, USA, 2006.
- **J. Schrofel, K. Novotný** : *Optické vlnovody*, SNTL, 1986
- **Saaleh**, *Fotonika* (1 - 4), Matfyzpres
- **S. R. Nagel, J. B. McChesney, K. L. Walker** : *An overview of the MCVD process and performance*, IEEE J. Quantum Electron. QE-18 (1982) 459-477
- Československý časopis pro fyziku 1/2010, 4-5/2010, 1/2011
- Jemná mechanika a optika 55 (2010)
- Sdělovací technika 3/2011

Uplatnění v oboru



UCHP - Oddělení aerosolových a laserových studií : Laserová ablační příprava nanostrukturovaných prášků, RNDr. Vladislav Dřínek, CSc., PROJEKT MAGISTERSKÉHO/BAKALÁŘKÉHO STUDIA

UCHP - Oddělení aerosolových a laserových studií : Laserová ablační příprava nanostrukturovaných prášků v kryogenních atmosférách RNDr. Vladislav Dřínek, CSc., PROJEKT DOKTORSKÉHO STUDIA

ALMA - Akademická laboratoř materiálového průzkumu malířských děl , RNDr. Janka Hradilová